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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2811

Examiner Hung K. Vu

In Re PATENT APPLICATION Of:

Applicants: Junichi HIKITA et al.

Serial No: 10/797,018

Filed: March 11, 2004

For: SEMICONDUCTOR CHIP AND
PRODUCTION THEREOF, AND
SEMICONDUCTOR DEVICE

Docket No.: AI 257D1

**INFORMATION
DISCLOSURE
STATEMENT**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This is an Information Disclosure Statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97(c)(2), i.e., after a first Office Action on the merits but before Final Rejection and/or Notice of Allowance.

Attached are copies of two Japanese Unexamined Patent Publications: No. 9-331004 and No. 2000-195900 and their English-language translations. The Japanese publications were cited in a Japanese Office Action dated September 13, 2005 for the corresponding Japanese Patent Application No. 11-029842. Any relevance of the Japanese publications can be gleaned from the English translations. The publications are listed on the attached Form PTO-1449. Consideration of the documents is respectfully requested.

It is hereby certified that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.

Respectfully submitted,

October 4, 2005

Date

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FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT		Atty Docket AI 257D1		Application No. 10/797,018			
		Applicant Junichi HIKITA et al.					
		Filing Date March 11, 2004		Group Unit 2811			
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA						
	AB						
	AG						
	AD						
	AE						
	AF						
	AG						
	AH						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub-Class	Translation
	AI	JP09-331004	12/22/97	Japan			Yes
	AJ	JP2000-195900	07/14/00	Japan			Yes
	AK						
	AL						
	AM						
	AN						
	AO						
OTHER (Including Author, Title, Date, Pertinent Pages, etc.)							
	AP						
	AQ						
	AR						
Examiner					Date Considered		
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							